

# AN11866

## BGU6102 Low Noise Amplifier for ISM / LTE bands

Rev. 1.0 — December 12, 2016

Application note

### Document information

Info	Content
<b>Keywords</b>	BGU6102 Low Noise Amplifier, 2.4 GHz LNA, 2.4-2.5 GHz ISM, WiFi (WLAN)
<b>Abstract</b>	This document provides circuit schematic, layout, BOM and evaluation board performance for an LNA based on a BGU6102.
<b>Ordering info</b>	BGU610x starter kit OM17056, 12nc 9340 707 06598
<b>Contact information</b>	For more information, please visit: <a href="http://www.nxp.com">http://www.nxp.com</a>



## Revision history

Rev	Date	Description
1.0	December 12, 2016	First version

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## 1. Introduction

The overall intent of this application note is to demonstrate the performance of the BGU6102 in multiple frequency bands.

- 70 - 130 MHz (FM)
- 40 - 1000 MHz (Broadband)
- 169 MHz (ISM)
- 433 MHz (ISM)
- 700 - 930 MHz (ISM / LTE)
- 2.4 - 2.5 GHz (ISM)
- 1.8 - 2.2 GHz (LTE)

In this application note the ISM/LTE band of 700 – 930 MHz and ISM band of 1.8 – 2.2 GHz are addressed. Key requirements for these applications are gain, noise figure, and input/output return loss.

The transistors of the BGU610X family are promoted with a full promotion package, called “starter kits” (one kit type per device type). Those kits include a BGU610X LNA evaluation board (see figure 1), transistors and simulation model parameters required to perform simulations. See the overview of available starter kits in the table below:

**Table 1. Customer evaluation kits**

	Basic type	Customer Evaluation kits
1	BGU6101	OM17055, starter kit for BGU6101, ISM/LTE 700-930 MHz and ISM 1.8-2.2 GHz
2	BGU6102	OM17056, starter kit for BGU6102, ISM/LTE 700-930 MHz and ISM 1.8-2.2 GHz
3	BGU6104	OM17057, starter kit for BGU6104, ISM/LTE 700-930 MHz and ISM 1.8-2.2 GHz

The BGU610X LNA evaluation board simplifies the evaluation of the BGU6102 application. The evaluation board enables testing of the device performance and requires no additional support circuitry. The board is fully assembled with the BGU6102 MMIC, and the necessary matching and decoupling components for the associated frequency band.

The board is also supplied with two SMA connectors for input and output connection to RF test equipment. A 50 ohm “through line” is provided at the top of the evaluation board in case the user wishes to verify RF connector and grounded coplanar waveguide losses for de-embedding purposes.

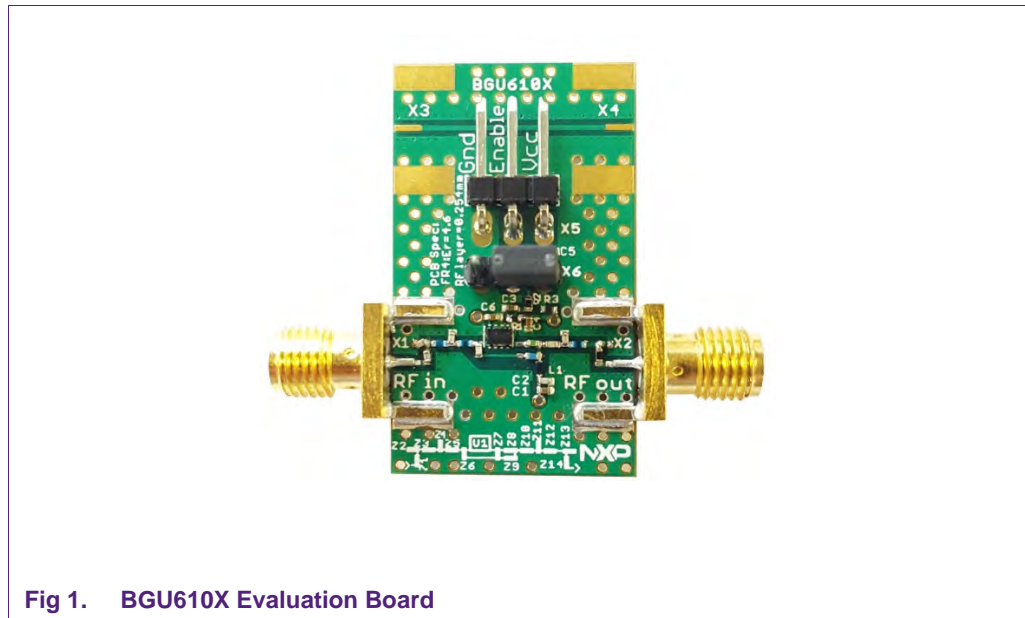


Fig 1. BGU610X Evaluation Board

## 2. Design and Application

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The BGU6102 MMIC is an unmatched wideband MMIC featuring an integrated bias, enable function and wide supply voltage. BGU6102 is part of a family of three products (BGU6101, BGU6102 and BGU6104).

Two applications are evaluated in this application note. One application covers the ISM/LTE band of 700 – 930 MHz and the other covers the ISM band of 1.8 – 2.2 GHz.

### Key Benefits:

- Supply voltage range from 1.5 V to 5 V
- Current range up to 20 mA@3 V, 40 mA@5 V
- $NF_{min}$  of 0.7 dB
- Applicable between 40 MHz and 4 GHz
- Integrated temperature-stabilized bias for easy design
- Bias current configurable with external resistor
- Power-down mode current consumption < 6  $\mu$ A
- ESD protection on all pins up to 3 kV HBM
- Small 6-pin leadless package 2.0 mm  $\times$  1.3 mm  $\times$  0.35 mm

### 2.1 Application Circuit Schematic

The PCB is designed to be adaptable for multiple bands. This way, only some components need to be exchanged in order to adjust the board for another frequency band (see figure 2).

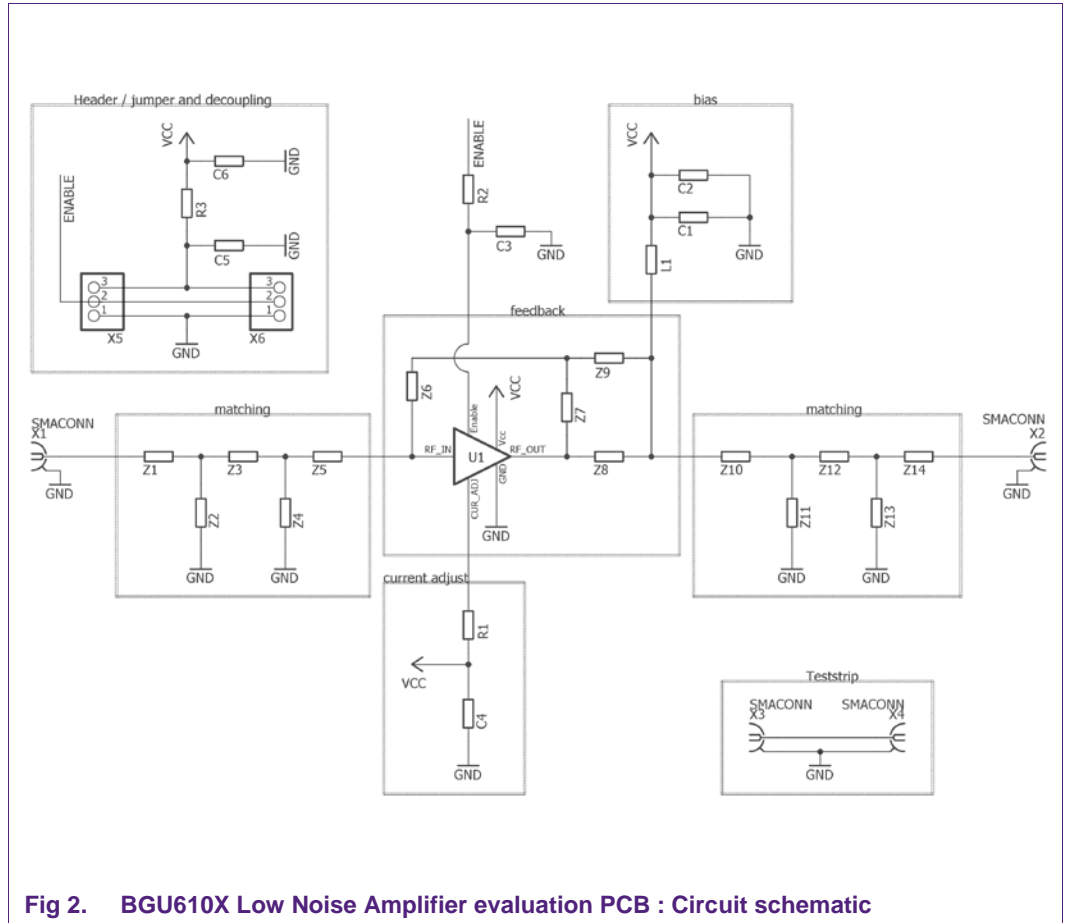


Fig 2. BGU610X Low Noise Amplifier evaluation PCB : Circuit schematic

## 2.2 Evaluation board Layout

Characteristics of the evaluation board (see figure 3):

- 3 layer PCB
- PCB material FR4 ( $\epsilon_r=4.6$ )
- 20 x 35 mm
- RF layer thickness 0.254 mm (critical)
- Surface finish ENIG (Electroless Nickel Immersion Gold)
- Soldermask
- SMD components (0402 formfactor)

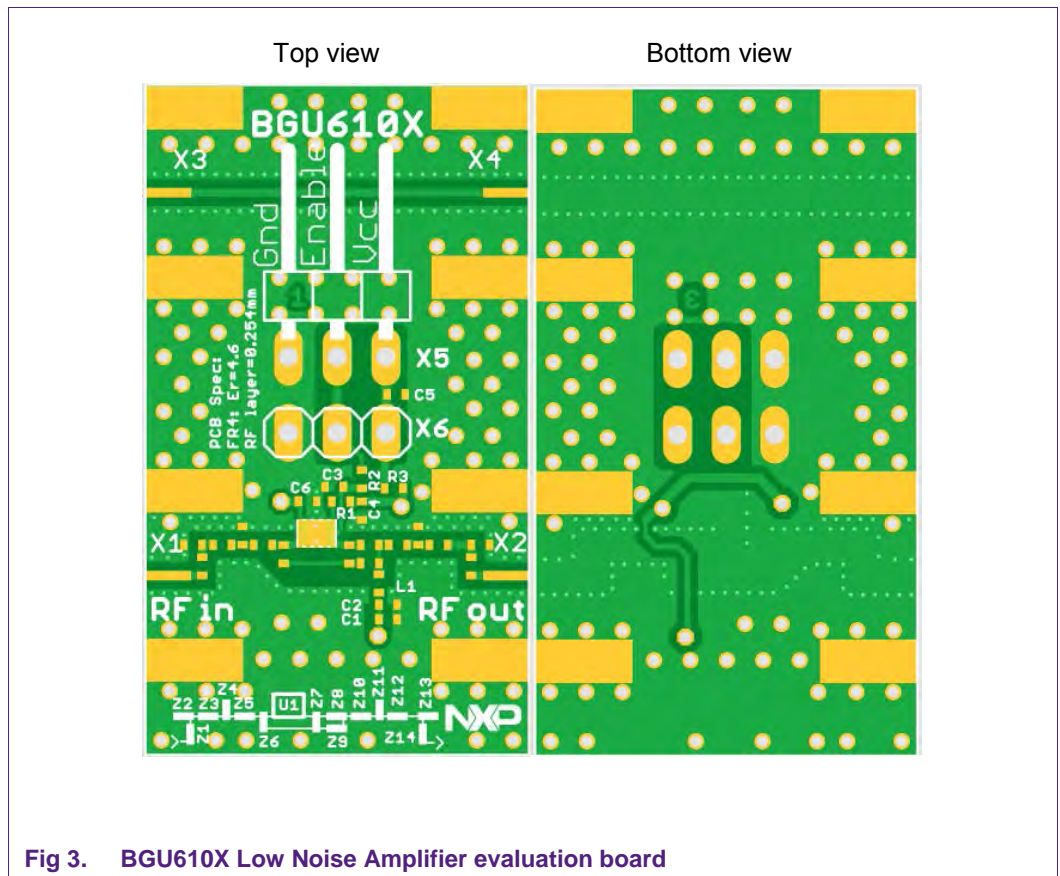
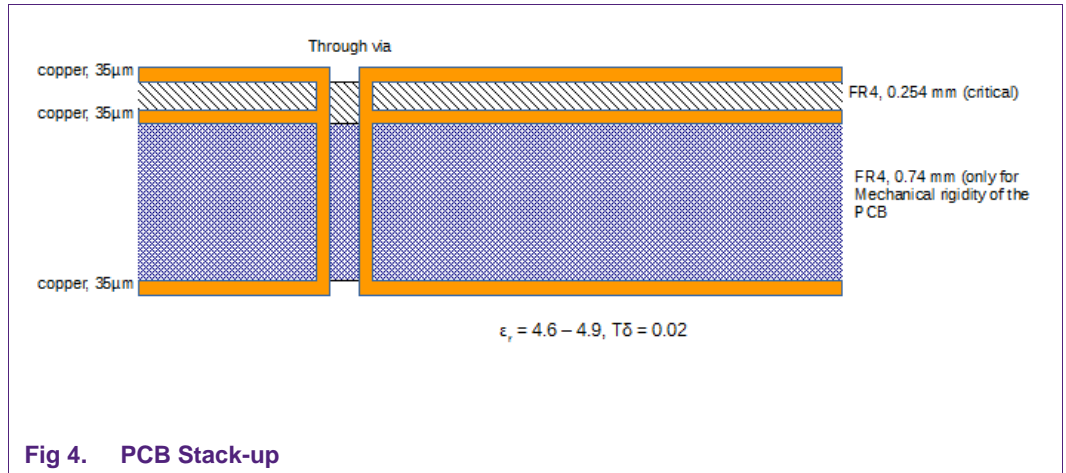


Fig 3. BGU610X Low Noise Amplifier evaluation board

Figure 4 shows the PCB stack-up. The PCB consists of 3 layers, where the first two, RF signal layer and RF ground are between a critical dielectric layer in order to ensure 50 ohm coplanar waveguide transmission lines. Through vias are used to connect the different layers.





## 2.3 Application board Bill-Of-Material

Table 2. Bill-Of-Material ISM / LTE 700 – 930 MHz

Item	Quantity	Reference	Part Number	Value	Vendor
1	4	Z1,Z6,Z10,C1	GRM1555C1H680GA01D	68pF	Murata
2	1	Z2	GJM1555C1H2R0WB01D	2.0pF	Murata
3	1	Z4	GJM1555C1H3R0WB01D	3.0pF	Murata
4	1	Z11	GJM1555C1H1R0BB01D	1.0pF	Murata
5	5	C2,C3,C4,C5,C6	GRM155R71A104KA01D	100nF	Murata
6	2	Z3,Z8	LQW15AN3N9B00D	3.9nH	Murata
7	1	Z5	LQW15AN5N6C10D	5.6nH	Murata
8	1	Z12	LQW15AN6N8J00D	6.8nH	Murata
9	1	Z13	LQG15HSR10J02D	100nH	Murata
10	1	L1	LQW15CNR27J10D	270nH	Murata
11	1	Z14	667-ERJ-2RKF15R0X	15	Panasonic - ECG
12	1	Z7	667-ERJ-2RKF7500X	750	Panasonic - ECG
13	1	R1	667-ERJ-2RKF9101X	9.1k	Panasonic - ECG
14	2	R2,R3	667-ERJ-2RKF10R0X	10	Panasonic - ECG
15	1	U1	BGU6102	-	NXP
16	2	X1,X2	142-0701-841	SMA	Cinch Connectivity
17	1	X5	538-22-28-8030	header	Molex
18	1	X6	538-22-28-4030	header	Molex

Note: Customer can choose their preferred vendor but should be aware that the performance could be affected.

Table 3. Bill-Of-Material LTE 1.8 – 2.2 GHz

Item	Quantity	Reference	Part Number	Value	Vendor
1	3	Z1,Z6,C1	GRM1555C1H150JA01D	15pF	Murata
2	1	Z2	GJM1555C1H1R9WB01D	1.9pF	Murata
3	1	Z4	GJM1555C1H4R2BB01D	4.2pF	Murata
4	1	Z11	GRM1555C1H1R0CA01D	1.0pF	Murata
5	1	Z12	GRM1555C1H5R6CA01D	5.6pF	Murata
5	5	C2,C3,C4,C5,C6	GRM155R71A104KA01D	100nF	Murata
6	1	Z3	LQG15HN1N8S02D	1.8nH	Murata
7	1	Z8	LQW15AN4N3B00D	4.3nH	Murata
8	1	Z13	LQW15AN6N2B00D	6.2nH	Murata
9	1	L1	LQW15CNR27J10D	270nH	Murata
10	1	Z14	ERJ-2GEJ6R8X	6.8	Panasonic - ECG
11	1	Z5	ERJ-2GE0R00X	0	Panasonic - ECG
12	1	Z9	ERJ-2RKF1201X	1.2k	Panasonic - ECG
13	1	Z10	ERJ-2RKF20R0X	15	Panasonic - ECG
14	1	R1	667-ERJ-2RKF9101X	9.1k	Panasonic - ECG
15	2	R2,R3	667-ERJ-2RKF10R0X	10	Panasonic - ECG
16	1	U1	BGU6102	-	NXP
17	2	X1,X2	142-0701-841	SMA	Cinch Connectivity
18	1	X5	538-22-28-8030	header	Molex
19	1	X6	538-22-28-4030	Header	Molex

Note: Customer can choose their preferred vendor but should be aware that the performance could be affected.

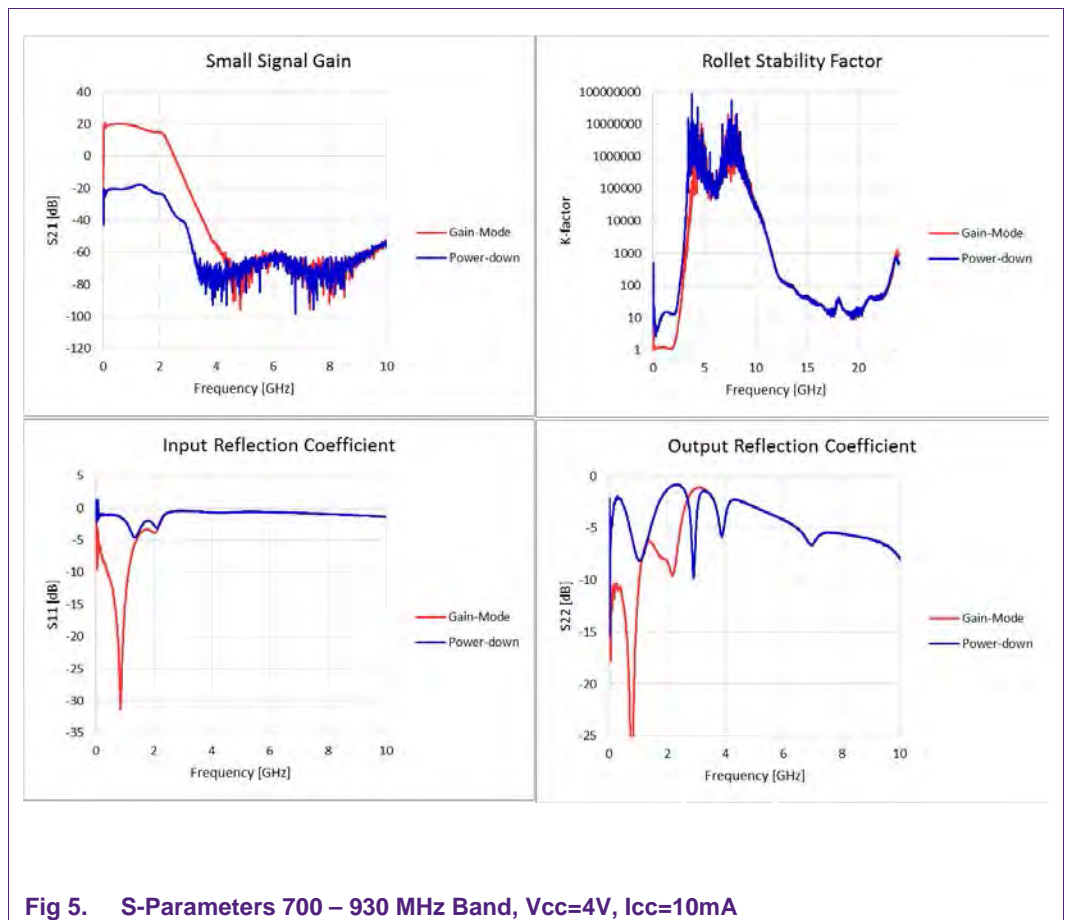
### 3. Measurement results ISM / LTE 700 – 930 MHz

This section presents the results of the BGU6102 Low Noise Amplifier. Unless otherwise noted, all measurement references are at the SMA connectors on the evaluation board and are performed at an ambient temperature of 25 degrees Celsius. The circuit is biased with  $V_{cc}=4V$ ,  $I_{cc}=10mA$ .

Next measurements are performed:

- S-parameters
- Noise figure
- RF-power characteristics
- Stability
- On/Off switching (Power-down)

#### 3.1 S-Parameters



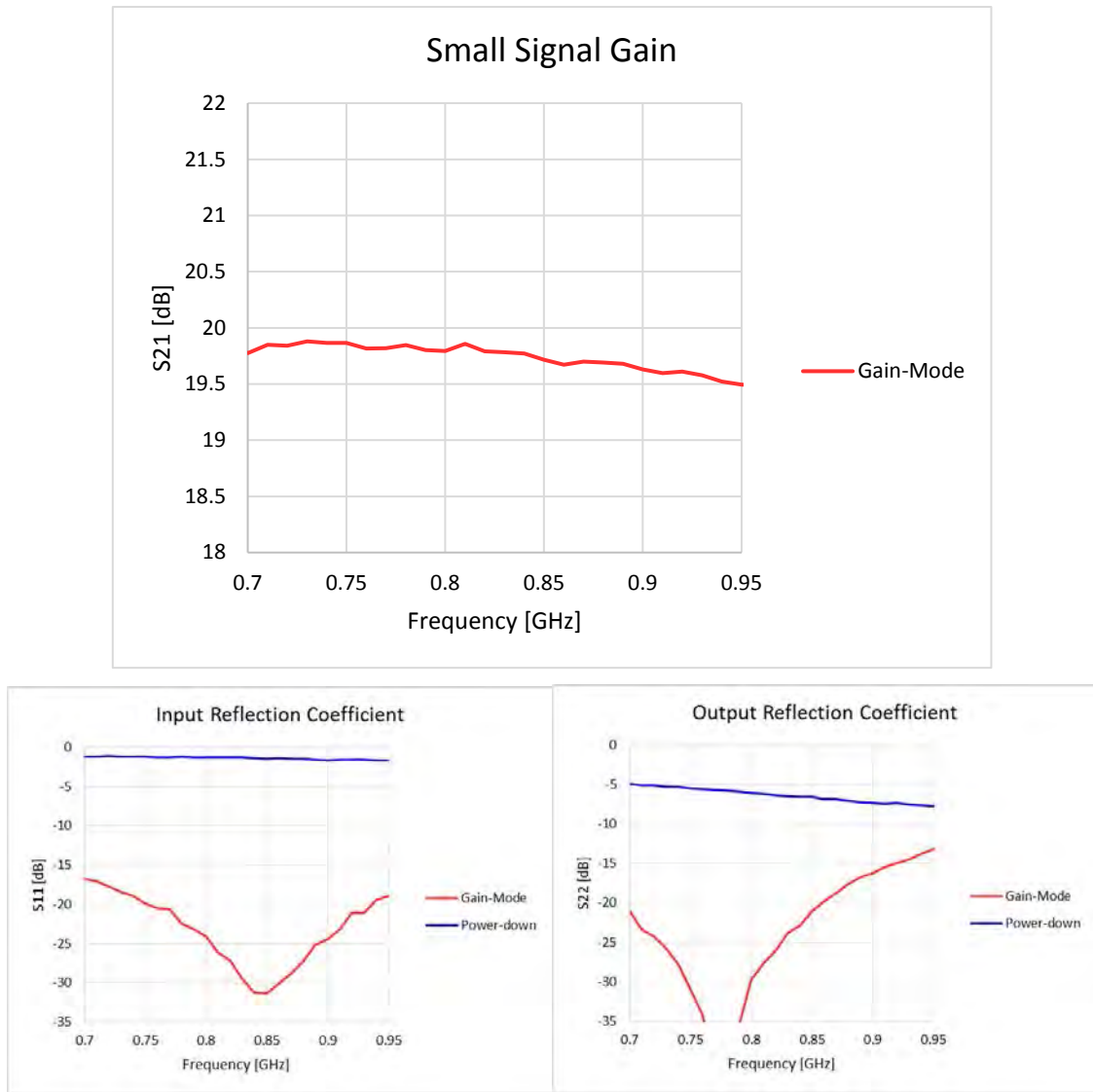
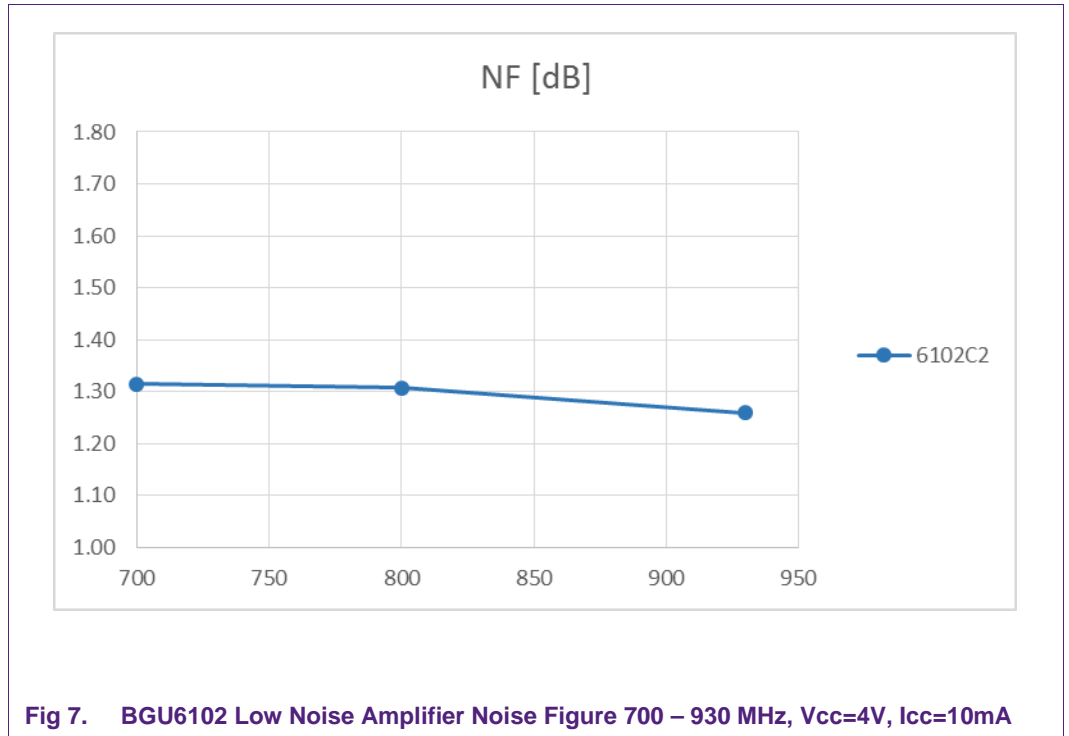


Fig 6. BGU6102 S-Parameters (typical values). Gain mode and Power-down mode (Frequency range zoomed in), Vcc=4V, Icc=10mA

### 3.2 Noise figure

The noise figure is physically measured at the SMA connectors of the evaluation board.



### 3.3 RF-power characteristics

Next paragraphs contains the linearity related characteristics of the BGU6102. The circuit is biased with  $V_{cc}=4V$ ,  $I_{cc}=10\text{ mA}$ .

#### 3.3.1 P1dB

Frequency [MHz]	iP1dB [dBm]	oIP1dB [dBm]
700	-16.7	1.9
800	-16.5	2.0
930	-16.5	1.9

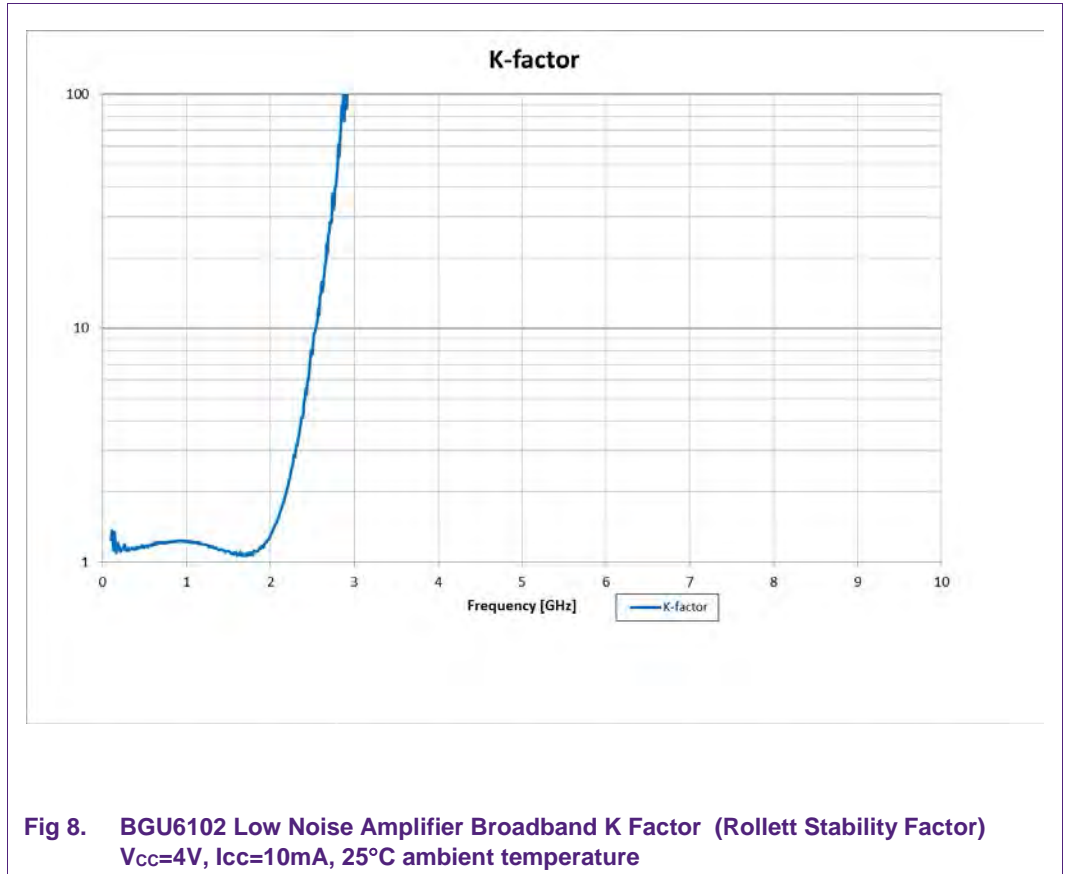
#### 3.3.2 IP3

The output-referred IP3 level for the BGU6102 is measured at -30dBm per tone with a frequency spacing of 1MHz at 700, 800 and 930MHz.

Frequency [MHz]	iIP3 [dBm]	oIP3 [dBm]
700	-7.6	12.2
800	-7.2	12.6
930	-6.5	13.1

### 3.4 Stability

The stability factor K is calculated from the measured S-parameters. To check for instabilities out of band, the S-parameters are measured over an extended frequency range.



### 3.5 LNA Turn ON-OFF Time

The evaluation board contains an RC low pass filter at the enable signal. This RC circuit introduces an extended on-off time and masks the on-off time of the device itself.

On-time = 1.3 us, Off-time = 4.5 us.

Conditions:

- trigger signal 0-4V 50% duty cycle, 200 Hz
- trigger level @ 50%
- input CW -20 dBm@900 MHz

The following diagram shows the setup to test LNA Turn ON and Turn OFF time.

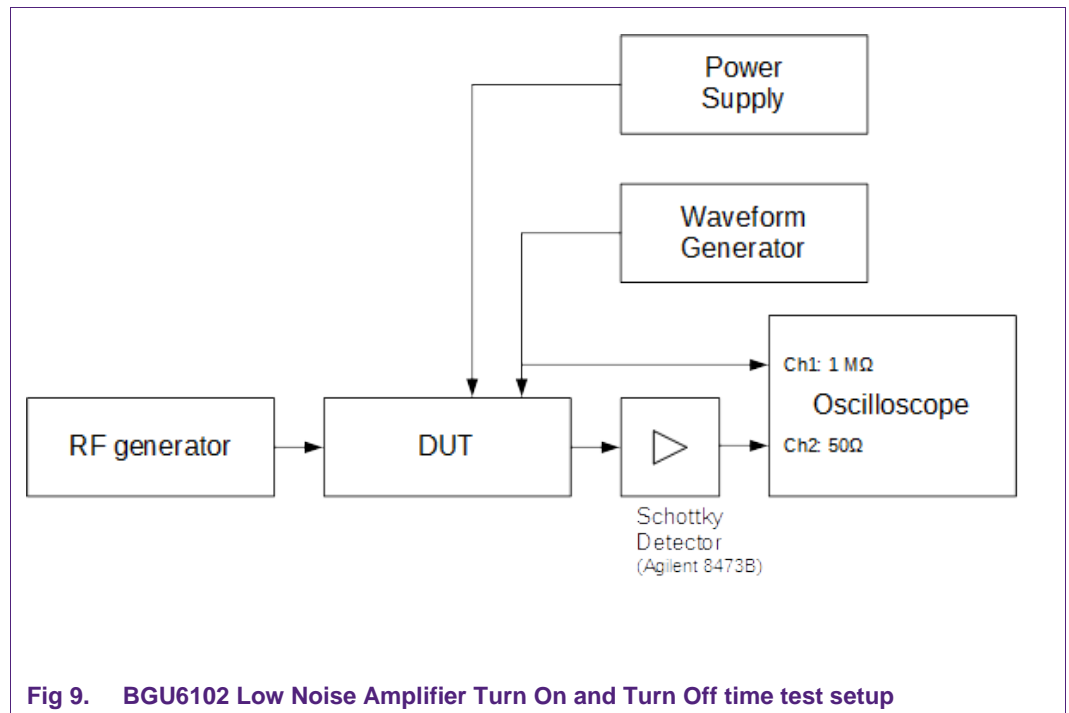


Fig 9. BGU6102 Low Noise Amplifier Turn On and Turn Off time test setup



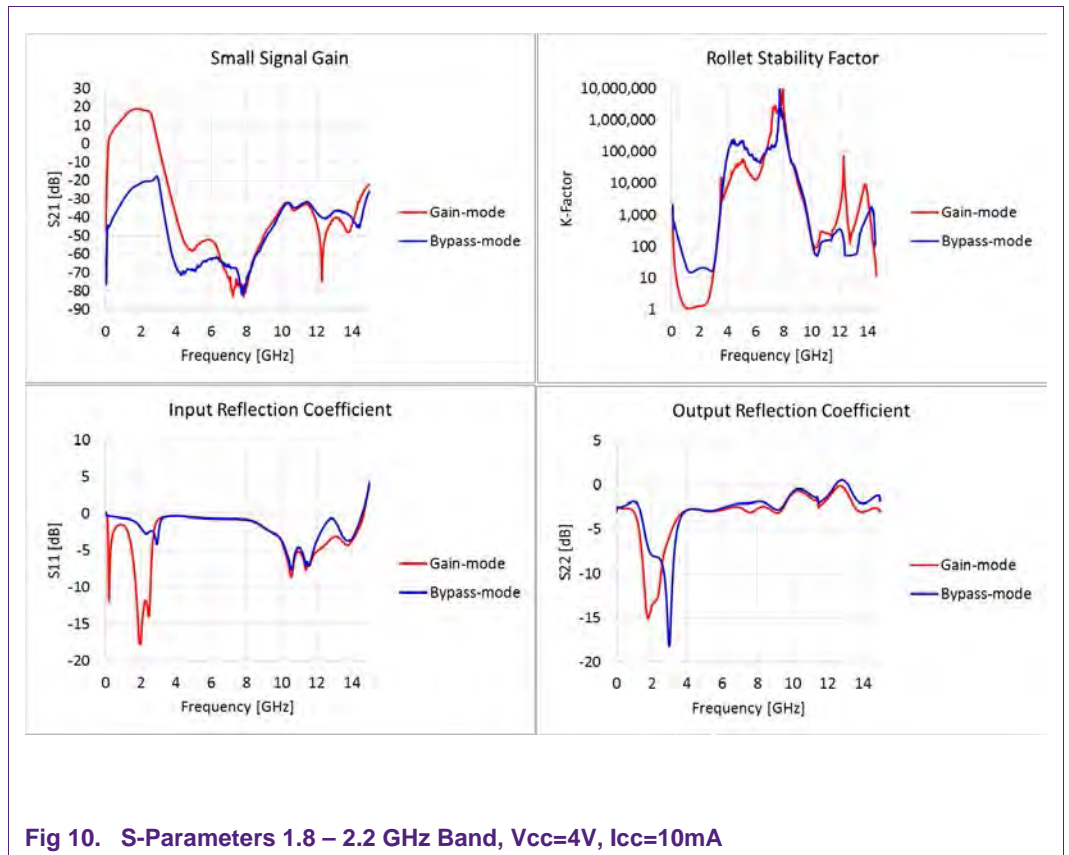
## 4. Measurement results LTE 1.8 – 2.2 GHz

This section presents the results of the BGU6102 Low Noise Amplifier for the LTE 1.8 – 2.2 GHz. Unless otherwise noted, all measurement references are at the SMA connectors on the evaluation board and are performed at an ambient temperature of 25 degrees Celsius. The circuit is biased with  $V_{cc}=4V$ ,  $I_{cc}=10mA$ .

Next measurements are performed:

- S-parameters
- Noise figure
- RF-power characteristics
- Stability
- On/Off switching

### 4.1 S-Parameters



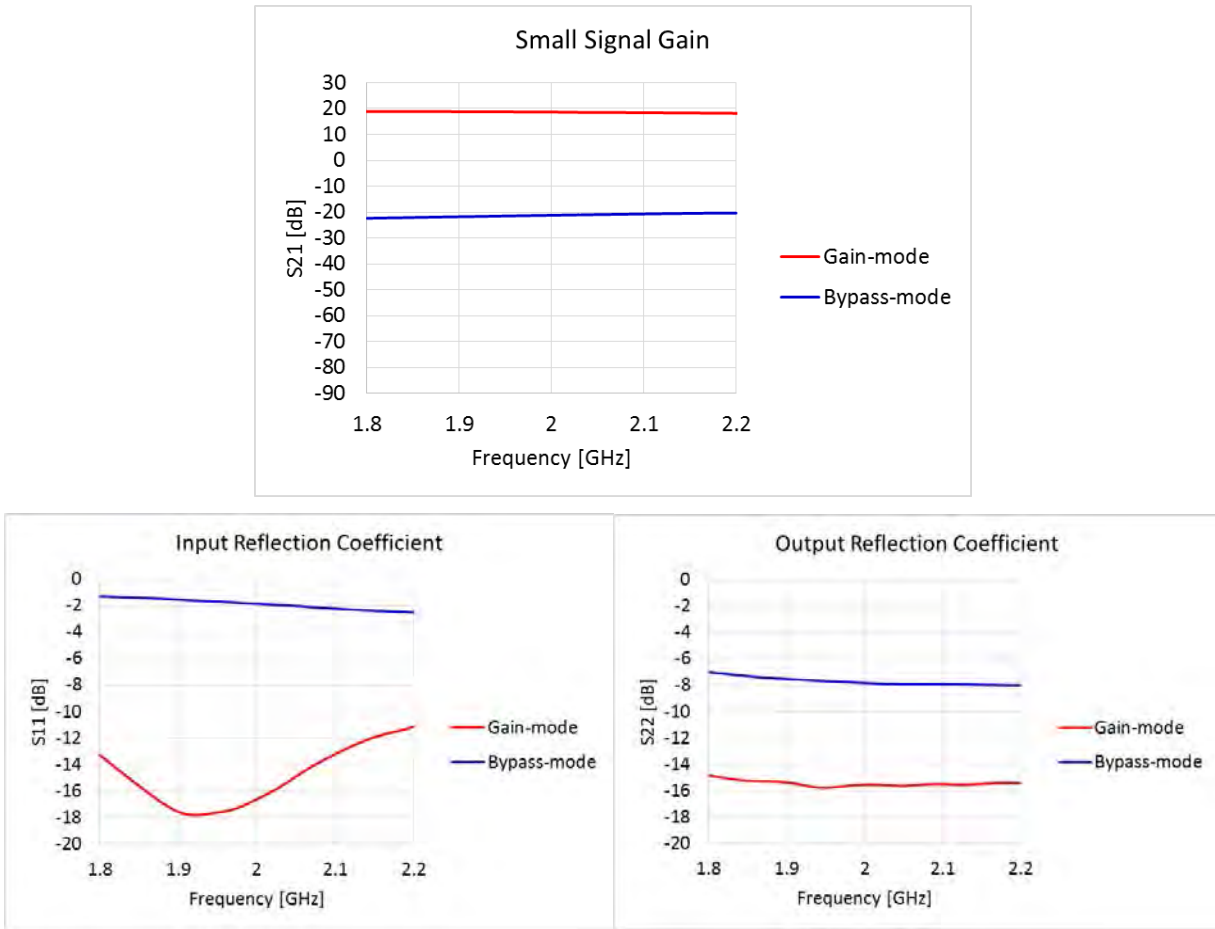


Fig 11. BGU6102 S-Parameters (typical values). Gain mode and Power-down mode (Frequency range zoomed in), Vcc=4V, Icc=10mA

4.2 Noise figure

The noise figure is physically measured at the SMA connectors of the evaluation board.

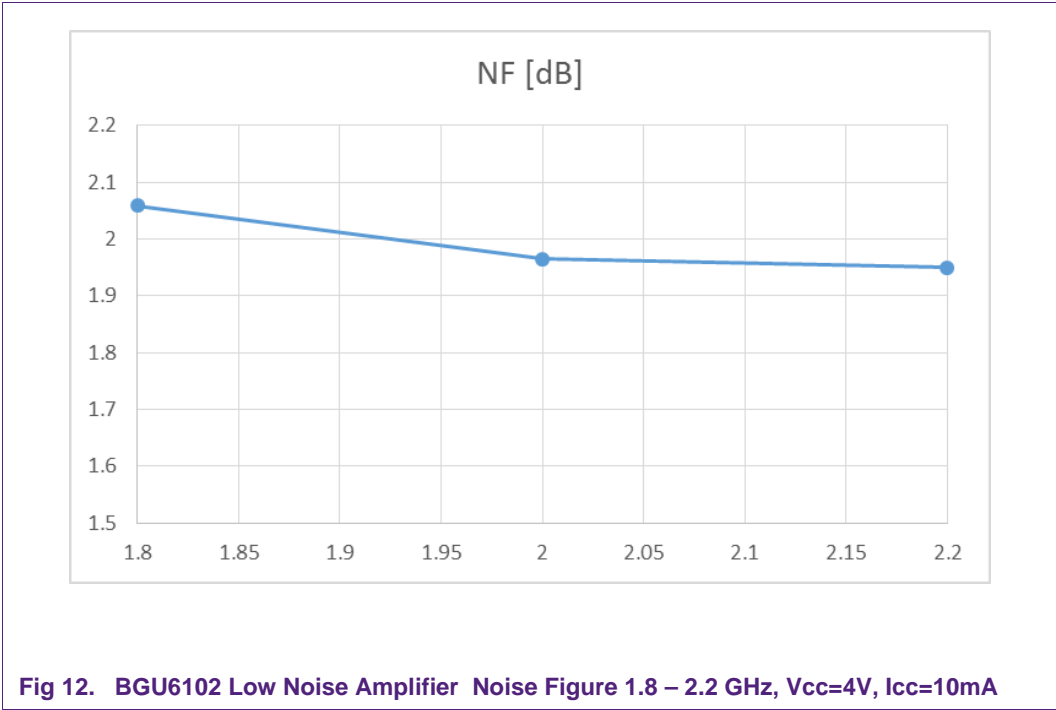


Fig 12. BGU6102 Low Noise Amplifier Noise Figure 1.8 – 2.2 GHz, Vcc=4V, Icc=10mA

### 4.3 RF-power characteristics

Next paragraphs contains the linearity related characteristics of the BGU6102. The circuit is biased with  $V_{cc}=4V$ ,  $I_{cc}=10\text{ mA}$ .

#### 4.3.1 P1dB

Frequency [GHz]	iP1dB [dBm]	oIP1dB [dBm]
1.8	-16.5	1.8
2.0	-14.4	3.5
2.2	-14.4	2.7

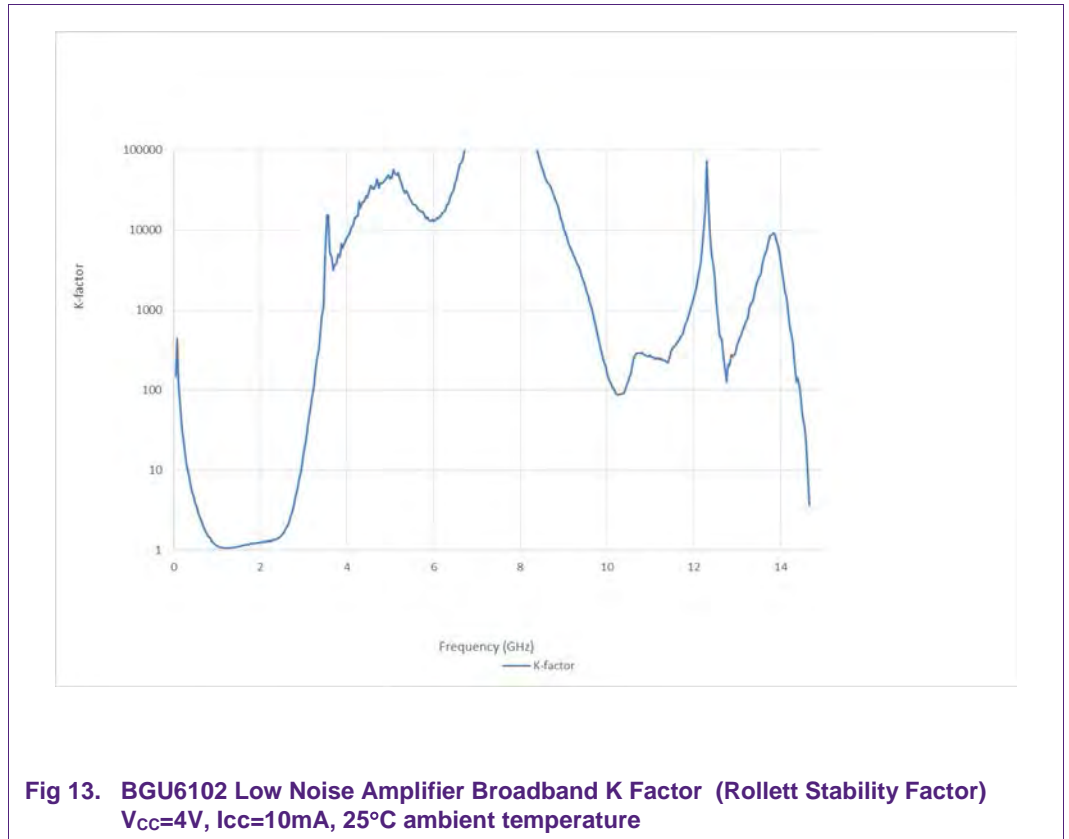
#### 4.3.2 IP3

The output-referred IP3 level for the BGU6102 is measured at -30dBm per tone with a frequency spacing of 1MHz at 1.8, 2.0 and 2.2GHz.

Frequency [GHz]	iIP3 [dBm]	oIP3 [dBm]
1.8	-7.4	11.4
2.0	-7.6	10.9
2.2	-6.2	11.8

#### 4.4 Stability

The stability factor K is calculated from the measured S-parameters. To check for out of band instabilities, the S-parameters are measured over an extended frequency range.



#### 4.5 LNA Turn ON-OFF Time

See paragraph 3.5 for the LNA turn ON-OFF time due to circuit similarity.

## 5. Summary measurement results ISM / LTE 700 – 930 MHz

**Table 4. Results measured on the BGU610X Low Noise Amplifier Evaluation Board for ISM / LTE 700 – 930 MHz**

Tamb = 25 °C; Ven = 4 V; Icc(tot) = 10 mA

Parameter		Symbol	Value	Unit
Supply Voltage		Vcc	4	V
Supply Current		Icc	10	mA
Noise Figure <sup>[1]</sup>	@ 700 MHz	NF	1.3	dB
	@ 930 MHz	NF	1.3	dB
Power Gain	@ 700 MHz	Gp	19.8	dB
	@ 930 MHz	Gp	19.6	dB
Input Return Loss	@ 700 MHz	IRL	17.8	dB
	@ 930 MHz	IRL	21.2	dB
Output Return Loss	@ 700 MHz	ORL	21.2	dB
	@ 930 MHz	ORL	14.5	dB
Reverse Isolation	@ 700 MHz	ISLrev	25.7	dB
	@ 930 MHz	ISLrev	25.8	dB
Input 1dB Gain Compression Point	@ 800 MHz	iP1dB	-16.5	dBm
Output 1dB Gain Compression Point	@ 800 MHz	oP1dB	2.0	dBm
Input Third Order Intercept Point <sup>[2]</sup>	@ 800 MHz	iIP3	-7.2	dBm
Output Third Order Intercept Point <sup>[2]</sup>	@ 800 MHz	oIP3	12.6	dBm
Stability ( 100 MHz - 15 GHz )		K	>1	
LNA Turn ON/OFF Time		Ton	1.3	µs
		Toff	4.5	µs

[1] PCB and connector losses excluded.

[2] The third order intercept point is measured at -30 dBm per tone at RF\_IN (f<sub>1</sub> = 800 MHz; f<sub>2</sub> = 801 MHz)

## 6. Summary measurement results LTE 1.8 – 2.2 GHz

**Table 5. Results measured on the BGU610X Low Noise Amplifier Evaluation Board for LTE 1.8 – 2.2 GHz**

Tamb = 25 °C; Ven = 4 V; Icc(tot) = 10 mA

Parameter		Symbol	Value	Unit
Supply Voltage		Vcc	4	V
Supply Current		Icc	10	mA
Noise Figure <sup>[3]</sup>	@ 1.8 GHz	NF	2.1	dB
	@ 2.2 GHz	NF	2.0	dB
Power Gain	@ 1.8 GHz	Gp	19.5	dB
	@ 2.2 GHz	Gp	18.3	dB
Input Return Loss	@ 1.8 GHz	IRL	13.3	dB
	@ 2.2 GHz	IRL	11.2	dB
Output Return Loss	@ 1.8 GHz	ORL	14.9	dB
	@ 2.2 GHz	ORL	15.5	dB
Reverse Isolation	@ 1.8 GHz	ISLrev	25.8	dB
	@ 2.2 GHz	ISLrev	26.6	dB
Input 1dB Gain Compression Point	@ 2.0 GHz	iP1dB	-14.4	dBm
Output 1dB Gain Compression Point	@ 2.0 GHz	oP1dB	3.5	dBm
Input Third Order Intercept Point <sup>[4]</sup>	@ 2.0 GHz	iIP3	-7.6	dBm
Output Third Order Intercept Point <sup>[4]</sup>	@ 2.0 GHz	oIP3	10.9	dBm
Stability ( 100 MHz - 10 GHz )		K	>1	
LNA Turn ON/OFF Time		Ton	1.3	µs
		Toff	4.5	µs

[3] PCB and connector losses excluded.

[4] The third order intercept point is measured at -30 dBm per tone at RF\_IN (f<sub>1</sub> = 2.000 GHz; f<sub>2</sub> = 2.001 GHz)

## 7. Application recommendations

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The BGU6102 can be used for other application than the applications mentioned in this application note. Only the matching components need to be changed (see schematic diagram of figure 2). The biasing components can be changed to improve the linearity performance.



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Please be aware that important notices concerning this document and the product(s) described herein, have been included in the section 'Legal information'.

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